

Enhancement Mode N-Channel Power MOSFET

 $TO-252/NMOS/40V/\pm20V/1.9V/60A/5.5m\Omega$

Rev_{0.6}





40V, 5.5mΩ, 60A, Single N-Channel

1.Features

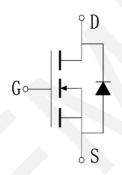
- ◆ 40V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V

2.Ap	pl	lica	tio	ns
- ~P	ρ.			

- ◆ Power Switching Application
- Load Switching



V _{DS}	R _{DS(on)} Typ.	I _D Max.
40) (5.5mΩ @ 10V	004
40V	7.5mΩ @ 4.5V	60A



Schematic Diagram

3. Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP4060K	WP4060K	TO-252	2500	25000

4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	$V_{ extsf{DSS}}$	40	٧
Gate to Source Voltage	V _{GSS}	±20	V
Drain Current (DC)	I _D	60	А
Drain Current (Pulse), PW≤300µs	I _{DP}	320	А
Total Dissipation	P _D	80	W
Avalanche Energy, Single Pulsed	E _{AS}	196	mJ
Junction Temperature	T _j	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction to Case	$R_{ heta JC}$	2.8	°C/W

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

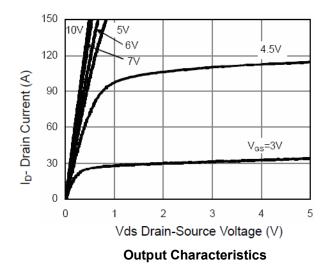
6.Electrical Characteristics at Ta=25°C (Note 3)

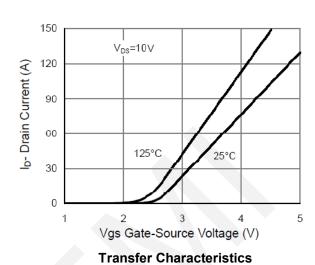
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain to Source Breakdown Voltage	V _{(BR)DSS}	$I_D = 250 \mu A, V_{GS} = 0 V$	40			V
Zero-Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 20V, V_{GS} = 0V$			1	μA
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 12V, V_{DS} = 0V$			±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{DS}=250\mu A$	1	1.9	2.5	V
Static Drain to Source On-State	Б	I _D = 20A, V _{GS} = 10V	-	5.5	7	mΩ
Resistance	R _{DS(on)}	$I_D = 10A, V_{GS} = 4.5V$	-	7.5	13	mΩ
Forward Transconductance	G_{FS}	I _D = 20A, V _{DS} = 10V	15			S
Input Capacitance	C _{iss}	V _{GS} =0V,		2662		pF
Output Capacitance	C _{oss}	V _{DS} =20V,		322		pF
Reverse Transfer Capacitance	C _{rss}	Frequency=1.0MHz		246		pF
Turn-ON Delay Time	t _{d(on)}			12		ns
Rise Time	t _r	$V_{DD} = 20V, R_L = 1\Omega$		11		ns
Turn-OFF Delay Time	$t_{d(off)}$	$V_{GS} = 10V, R_G = 3\Omega$		39		ns
Fall Time	t _f			12		ns
	Qg	V _{DS} = 20V,		54.3		nC
Total Gate Charge	Q _{gs}	V _{GS} = 10V, I _D = 20A		6.9		nC
	Q_{gd}			14.5		nC
Diode Forward Voltage	V_{FSD}	I _S = 10A, V _{GS} = 0		0.85	1.2	V

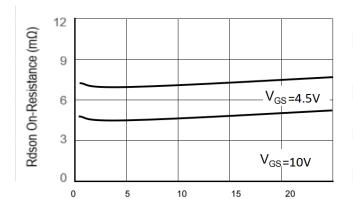
Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

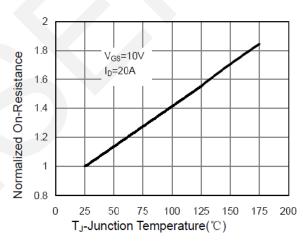


7. Typical electrical and thermal characteristics





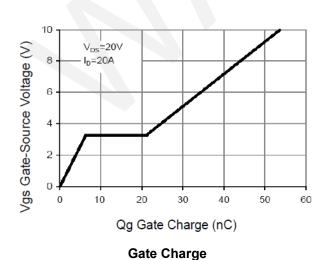


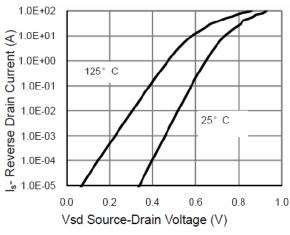


Rdson-Drain Current

I_D- Drain Current (A)

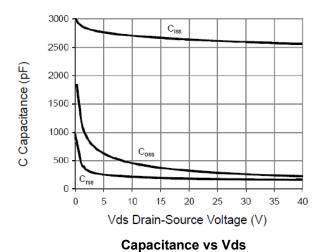
Rdson-Junction Temperature

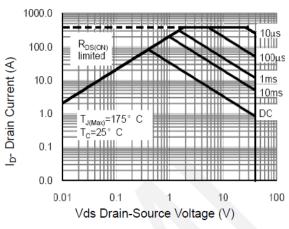




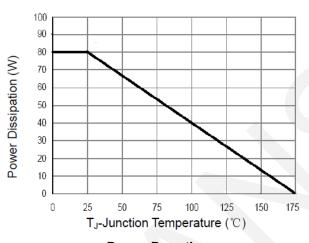
Source-Drain Diode Forward

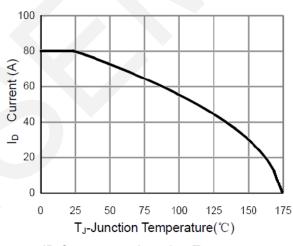






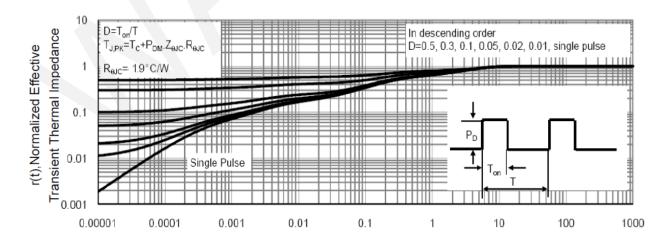
Safe Operation Area





Power De-rating

ID Current vs. Junction Temperature

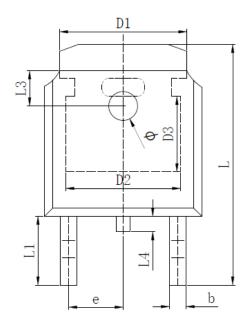


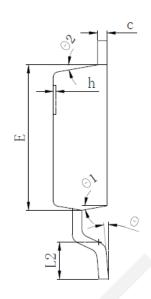
Square Wave Pluse Duration(sec)

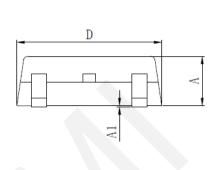
Normalized Maximum Transient Thermal Impedance



8.Package Dimensions







SYMBOL	MILLIMETER			
SIMDUL	MIN	Тур.	MAX	
A	2. 200	2. 300	2. 400	
A1	0.000		0. 127	
b	0.640	0.690	0. 740	
c(电镀后)	0. 460	0. 520	0. 580	
D	6. 500	6. 600	6. 700	
D1		5.334 REF		
D2		4.826 REF		
D3		3.166 REF		
E	6. 000	6. 100	6. 200	
е	2.286 TYP			
h	0.000	0. 100	0. 200	
L	9. 900	10. 100	10. 300	
L1	2.888 REF			
L2	1. 400	1. 550	1. 700	
L3	1.600 REF			
L4	0.600	0.800	1. 000	
ф	1. 100	1. 200	1. 300	
θ	0°		8°	
θ 1	9° TYP			
θ 2	9° TYP			



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